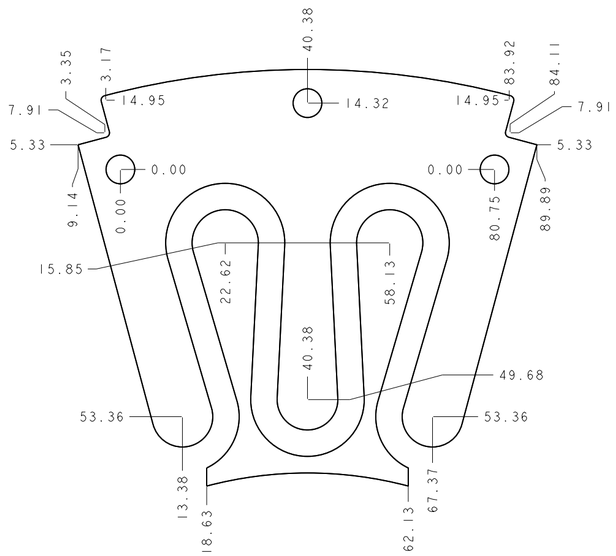
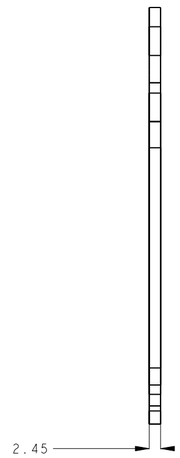
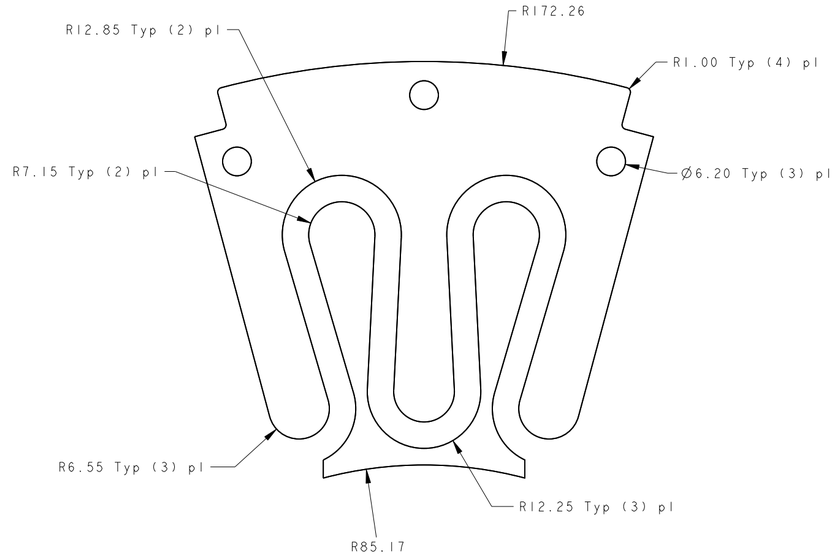
ITEM	PART NO	REQD	DESCRIPTION	MATERIAL







SCALE 1:1

REV	DWG	CHK	ZONE	DATE	CHANGES

UNLESS OTHERWISE SPECIFIED

TOLERANCES		
	X.X ± 0.5	FRAC. ± 1/64
	X.XX ± 0.05	Angles ± 1.00°
	X.XXX ± 0.010	FINISH 125 (µin)

DO NOT SCALE PRINT

THREADS ARE CLASS 2
CHAMFER ENDS OF ALL SCREW TREADS 30°
CUT ROUND, 1.5 THREAD RELIEF ON MACHINED THREADS
BREAK EDGES .016 MAX. ON MACHINED WORK
REMOVE BURRS, WELD SPLATTER & LOOSE SCALE
IN ACCORDANCE WITH ASME Y14.5M & B46.1

SHOP ORDERS

ACCT NO.	See J.O.	NO. REQD	60
DEL TO	Jon Wirth		
SURFACE TREATMT	-		
IDENT METHOD	TAG		
PROJECT NUMBER	ATL-IP-ED-0043		
PROJECT NAME	US ATLAS SILICON SUBSYSTEM		
DWG BY	J WIRTH	DATE	02-Jul-01
CHK BY	ANDERSSEN	DATE	2-JUL-01
APR BY	ANDERSSEN	DATE	

SER NO.	-
DATE ISSD	-
DATE REQD	-

US ATLAS SILICON SUBSYSTEM (logo)

ERNEST ORLANDO LAWRENCE
BERKELEY NATIONAL LABORATORY
UNIVERSITY OF CALIFORNIA - BERKELEY

ATLAS PIXEL DETECTOR
DISK SECTOR, MODULE LOCAL SUPPORT
SECTOR FOAM COMPLETE

MICROFILMED:	DWG. TYPE	SHOWN ON	SCALE: 1:1	DO NOT SCALE PRINTS
	PART		SHEET 1 OF 1	
PATENT CLEAR:	DESIGN ACCT. NO.	CATEGORY CODE	DWG. NO.	SIZE / REV.
	PIAP-11	AP6110	21F416-33	1

Dwg. File: 21F416-3 Model File: 21F416-3

Rev 1/8/2001 ATLAS

DWG. NO. 21F416-33 SIZE 1 REV. 1 SH. 1